

阅读申明

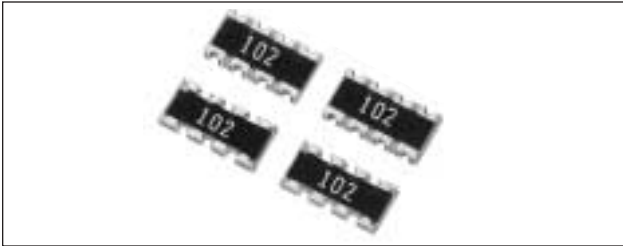
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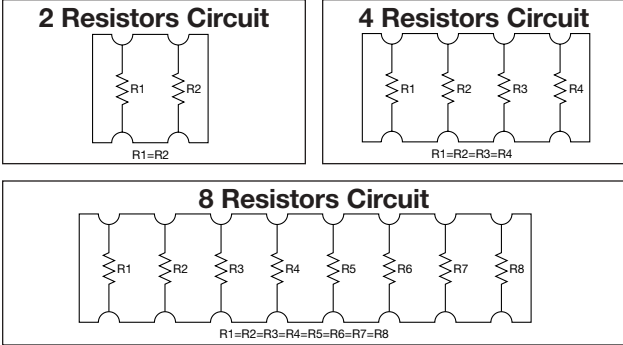
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Chip Resistor Arrays

CRB Series (Concave Type)



Chip Resistor Arrays have several resistor elements integrated as a single component.



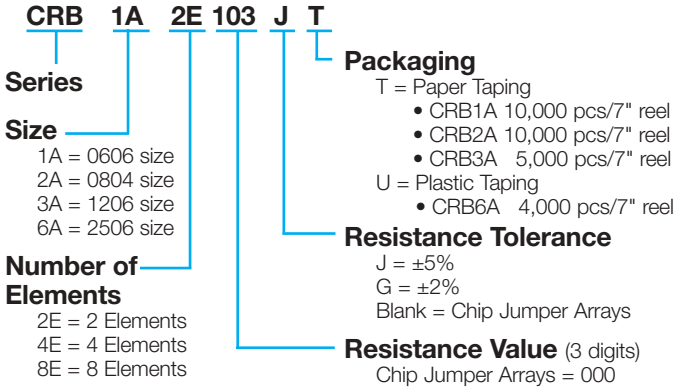
FEATURES

- Reduction in mounting process & costs
- Save PCB space
- Reduction of inventory control costs

APPLICATIONS

- Computer
- Hard Disk Drive
- Printer
- CD-ROM

HOW TO ORDER



RATING

Chip Resistor Arrays	
Item	Rating
Rated Power (70°C)*	1/16W Element
Max. Working Voltage	50V
Max. Overload Voltage	100V
Resistance Value	10Ω to 2.2MΩ (CRB6A 1MΩ max.)
Tolerance	J±5% (CRB6A G ± 2% only)
Working Temperature	-55 to +125°C

Chip Jumper Arrays	
Item	Rating
Rated Current	1A
Conductive Resistance Value	50MΩ max.
Resistance Value	Zero ohms (0 ± .5 ohms)
Working Temperature	-55 to +125°C

*Rated voltage = 50V or $\sqrt{\text{Rated power} \times \text{Resistance value}}$, whichever is less

DIMENSIONS

millimeters (inches)

Code	W	L	C	d	t	a	b	P	
CRB1A2E									
Dim.	1.60±0.15 (0.063±0.006)	1.60±0.20 (0.063±0.008)	0.30±0.20 (0.012±0.008)	0.40±0.15 (0.016±0.006)	0.60±0.10 (0.024±0.006)	0.50±0.15 (0.020±0.006)	0.30±0.10 (0.012±0.004)	0.80±0.10 (0.031±0.004)	
No Marking on chips									
Code	L	W	T	P	b	c	d	e	
CRB2A4E									
Dim.	2.00±0.10 (0.079±0.004)	1.00±0.10 (0.039±0.004)	0.40±0.10 (0.016±0.004)	0.50 typ (0.020 typ)	∅0.15 typ (∅0.006 typ)	0.20±0.15 (0.008±0.006)	0.25±0.015 (0.010±0.006)	0.25 typ (0.010 typ)	
Code	W	L	C	D	T	P			
CRB3A4E									
Dim.	1.60±0.15 (0.063±0.006)	3.20±0.15 (0.126±0.006)	0.30±0.20 (0.012±0.008)	0.40±0.15 (0.016±0.006)	0.60±0.10 (0.024±0.004)	0.80 typ (0.031 typ)			
Code	L	W	T	P	c	d	e (top)	e (bottom)	
CRB6A8E									
Dim.	6.40±0.20 (0.252±0.008)	1.60±0.20 (0.063±0.008)	0.60±0.10 (0.024±0.004)	0.80 typ (0.031 typ)	0.30±0.20 (0.012±0.008)	0.40±0.15 (0.016±0.006)	0.50±0.10 (0.020±0.004)	0.40±0.15 (0.016±0.006)	

Detailed specifications are available on request.

Chip Resistor Arrays



CR, CJ, CRA, CRB, CRC Series - Test Conditions

ELECTRICAL CHARACTERISTICS

Item	Standard		Test Conditions							
	Resistor	Jumper	Resistor	Jumper						
DC Resistance	Within Initial Tolerance		Power Condition A (20°C, 65% RH)							
Temperature Characteristics	<table border="1"> <thead> <tr> <th>Resistance (Ω)</th> <th>TCR (ppm/°C)</th> </tr> </thead> <tbody> <tr> <td>*D, F 10 ≤ R ≤ 1M</td> <td>-100 to +100</td> </tr> <tr> <td>J, CR05 = F R < 10 10 ≤ R ≤ 1M 1M < R</td> <td>-100 to +600 -250 to +250 -500 to +300</td> </tr> </tbody> </table>		Resistance (Ω)	TCR (ppm/°C)	*D, F 10 ≤ R ≤ 1M	-100 to +100	J, CR05 = F R < 10 10 ≤ R ≤ 1M 1M < R	-100 to +600 -250 to +250 -500 to +300	/	Test Temperature: 25, 125(°C) $\Delta R/R = R_2 - R_1 / R_1 \times 1 / T_2 - T_1 \times 10^6$ $\Delta R/R = \text{Temp. Coefficient (ppm/°C)}$ T ₁ = 25(°C) T ₂ = 125(°C) R ₁ = T ₁ Resistance at (Ω) R ₂ = T ₂ Resistance at (Ω)
	Resistance (Ω)	TCR (ppm/°C)								
*D, F 10 ≤ R ≤ 1M	-100 to +100									
J, CR05 = F R < 10 10 ≤ R ≤ 1M 1M < R	-100 to +600 -250 to +250 -500 to +300									
Short-time Overload	<table border="1"> <thead> <tr> <th>ΔR/R</th> <th>Visual</th> </tr> </thead> <tbody> <tr> <td>±(2.0%+0.10Ω) max. of the initial value</td> <td>No evidence of mechanical damage intermittent overload</td> </tr> </tbody> </table>	ΔR/R	Visual	±(2.0%+0.10Ω) max. of the initial value	No evidence of mechanical damage intermittent overload	50mΩ max.	(1) Apply 2.0 x rated voltage for 5 sec. (2.5 x rated voltage for Arrays) (2) Wait 30 minutes (3) Measure resistance CR03 = 30V max. CR05 = 50V max. CR10 = 100V max. CR21 = 200V max. CR32 = 400V max. CRA3A, CRB3A, CRC3A = 100V max.	(1) 2A for 5 sec. (CJ03 = 1A) (2) Wait 30 minutes (3) Measure resistance		
ΔR/R	Visual									
±(2.0%+0.10Ω) max. of the initial value	No evidence of mechanical damage intermittent overload									
Intermittent Overload	<table border="1"> <thead> <tr> <th>ΔR/R</th> <th>Visual</th> </tr> </thead> <tbody> <tr> <td>±(5%+0.1Ω) max. of the initial value</td> <td>No evidence of mechanical damage</td> </tr> </tbody> </table>	ΔR/R	Visual	±(5%+0.1Ω) max. of the initial value	No evidence of mechanical damage	50mΩ max.	(1) Perform 10,000 voltage cycles as follows: ON (2.0 x rated voltage, 2.5 x for Arrays) 1 sec. OFF 25 sec. (2) Stabilization time 30 min. without loading (3) Measure resistance CR03 = 30V max. CR05 = 50V max. CR10 = 150V max. CR21 = 200V max. CR32 = 400V max. CRA, CRB, CRC = 100V max.	(1) Perform 10,000 current cycles as follows: ON (2A) 1 sec. OFF 25 sec. (2) Wait 30 minutes (3) Measure resistance CJ03 = 1A max.		
	ΔR/R	Visual								
±(5%+0.1Ω) max. of the initial value	No evidence of mechanical damage									
Dielectric Withstanding Voltage	No evidence of mechanical damage		Apply 500 VAC for 1 min. (CR10 300 VAC) (CR05, CRA3A, CRB3A, CRC3A 300 VAC/1 sec. CR03 50 VAC/min.)							
Insulation Resistance	<ul style="list-style-type: none"> • CR03, CJ03 = 10⁸Ω min. • CR05, CJ05 = 10⁸Ω min. • CR10, CJ10 = 10⁹Ω min. • CR21, CJ21 = 10¹⁰Ω min. • CR32, CJ32 = 10¹²Ω min. • CRA3A, CRB3A, CRC3A = 10⁹Ω min. 		Apply 500V DC (CR05, CRA3A, CRB3A, CRC3A 100V DC CR03 50 VDC)							



Chip Resistor Arrays



CR, CJ, CRA, CRB, CRC Series - Test Conditions

MECHANICAL CHARACTERISTICS

Item		Standard		Test Conditions	
		Resistor	Jumper	Resistor	Jumper
Terminal Strength	$\Delta R/R$	$\pm(1\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Apply the load as shown: Measure resistance during load application	
	Visual	No evidence of mechanical damage after loading		<p>millimeters (inches)</p> <p>Bending in 10 seconds</p> <p>PC Board = Glass epoxy t = 1.60 (0.063)</p>	
Soldering Heat Resistance	$\Delta R/R$	$\pm(1\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Immerse into molten solder at 260 \pm 5 $^{\circ}$ C for 10 \pm 1 sec. Stabilize component at room temperature for 1 hr. Measure resistance.	
	Visual	No evidence of leaching			
Solderability		Coverage \geq 95% each termination end		Immerse in Rogin Flux for 2 \pm 0.5 sec. and in SN62 solder at 235 \pm 5 $^{\circ}$ C for 2 \pm 0.5 sec.	
Anti-Vibration Test	$\Delta R/R$	$\pm(1\%+0.1\Omega)$ max. of the initial value	50m Ω max.	2 hrs. each in X, Y and Z axis. (TTL 6 hrs.) 10 to 55 Hz sweep in 1 min. at 1.5mm amplitude.	
	Visual	No evidence of mechanical damage			
Solvent Resistance	$\Delta R/R$	$\pm(0.5\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Immerse in static state butyl acetate at 20 $^{\circ}$ C to 25 $^{\circ}$ C for 30 \pm 5 sec. Stabilize component at room temperature for 30 min. then measure value.	
	Visual	No evidence of mechanical damage			

ENVIRONMENTAL CHARACTERISTICS

Item		Standard		Test Conditions	
		Resistor	Jumper	Resistor	Jumper
Temperature Cycle	$\Delta R/R$	$\pm(1\%+0.05\Omega)$ max. of the initial value	50m Ω max.	(1) Run 5 cycles as follows: -55 \pm 3 $^{\circ}$ C for 30 min. 125 \pm 3 $^{\circ}$ C for 30 min. Room temp. for 10-15 min. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Low Temperature Storage	$\Delta R/R$	$\pm(2\%+0.1\Omega)$ max. of the initial value	50m Ω max.	(1) Dwell in -55 $^{\circ}$ C chamber without loading for 1000 $^{+48}$ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
High Temperature Storage	$\Delta R/R$	$\pm(3\%+0.1\Omega)$ max. of the initial value	50m Ω max.	(1) Dwell in 125 $^{\circ}$ C chamber without loading for 1000 $^{+48}$ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Moisture Resistance	$\Delta R/R$	$\pm(3\%+0.1\Omega)$ max. of the initial value	50m Ω max.	(1) Dwell in temp.: 65 $^{\circ}$ C RH90 to 95% RH chamber without loading for 1000 $^{+48}$ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Life Test	$\Delta R/R$	$\pm(3\%+0.1\Omega)$ max. of the initial value	50m Ω max.	(1) Temp.: 70 \pm 3 $^{\circ}$ C Voltage: (rated voltage) on 90 min. off 30 min. Duration: 1000 $^{+48}$ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Loading Life in Moisture	$\Delta R/R$	$\pm(3\%+0.1\Omega)$ max. of the initial value	50m Ω max.	(1) Temp.: 40 \pm 2 $^{\circ}$ C RH: 90-95% Voltage Cycle: on 90 min. (rated voltage) off 30 min. Duration: 1000 $^{+48}$ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			

Packaging of Chip Component

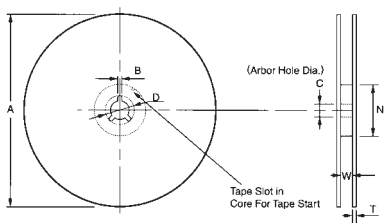


Automatic Insertion Packaging

TAPE AND REEL

REEL DIMENSIONS

millimeters (inches)

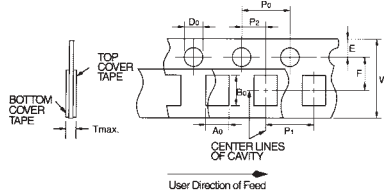


Tape Size	A Max.	B Min.	C	D Min.	N Min.	W	T Max.
8mm	178 (7)	1.50 (0.059)	13.0±0.50 (0.512±0.020)	20.2 (0.795)	50 (1.969)	10.0±1.50 (0.394±0.059)	2.50 (0.098)
	260 (10)						

Metric dimensions will govern.
English measurements rounded and for reference only.

millimeters (inches)

PUNCHED TAPE CONFIGURATION 8MM TAPE ONLY

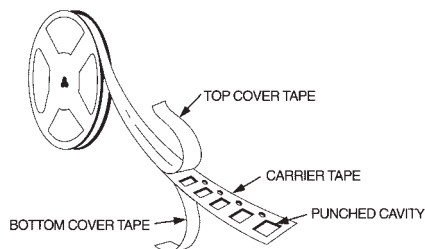


Tape Size	D ₀	E	P ₀	P ₂	W	F
8mm	1.50 ^{+0.10} / _{-0.00} (0.059 ^{+0.004} / _{-0.000})	1.75±0.10 (0.069±0.004)	4.0±0.10 (0.157±0.004)	2.00±0.05 (0.079±0.002)	8.00±0.20 (0.135±0.008)	3.50±0.05 (0.138±0.002)

VARIABLE DIMENSIONS

Style	P ₁	A ₀	B ₀	T max.
CR/CJ03 CR/CJ05	2.00±0.10 (0.079±0.004)	0.65±0.10 (0.026±0.004)	1.15±0.10 (0.045±0.004)	0.60 (0.024)
CR/CJ/FR10	4.00±0.10 (0.157±0.004) or 2.00±0.10 (0.079±0.004)	1.10±0.20 (0.043±0.008)	1.90±0.20 (0.075±0.008)	1.10 (0.043)
CR/CJ/FR21	4.00±0.10 (0.157±0.004)	1.65±0.20 (0.065±0.008)	2.40±0.20 (0.094±0.008)	
CR/CJ/FR32		2.00±0.20 (0.079±0.008)	3.60±0.20 (0.142±0.008)	
CRB1A		1.90±0.20 (0.075±0.008)	1.90±0.20 (0.075±0.008)	
CRA3A CRB3A CRC3A		2.00±0.20 (0.079±0.008)	3.60±0.20 (0.142±0.008)	
CRB2A		2.00±0.10 (0.079±0.004)	1.25±0.20 (0.049±0.008)	

PUNCHED CARRIER

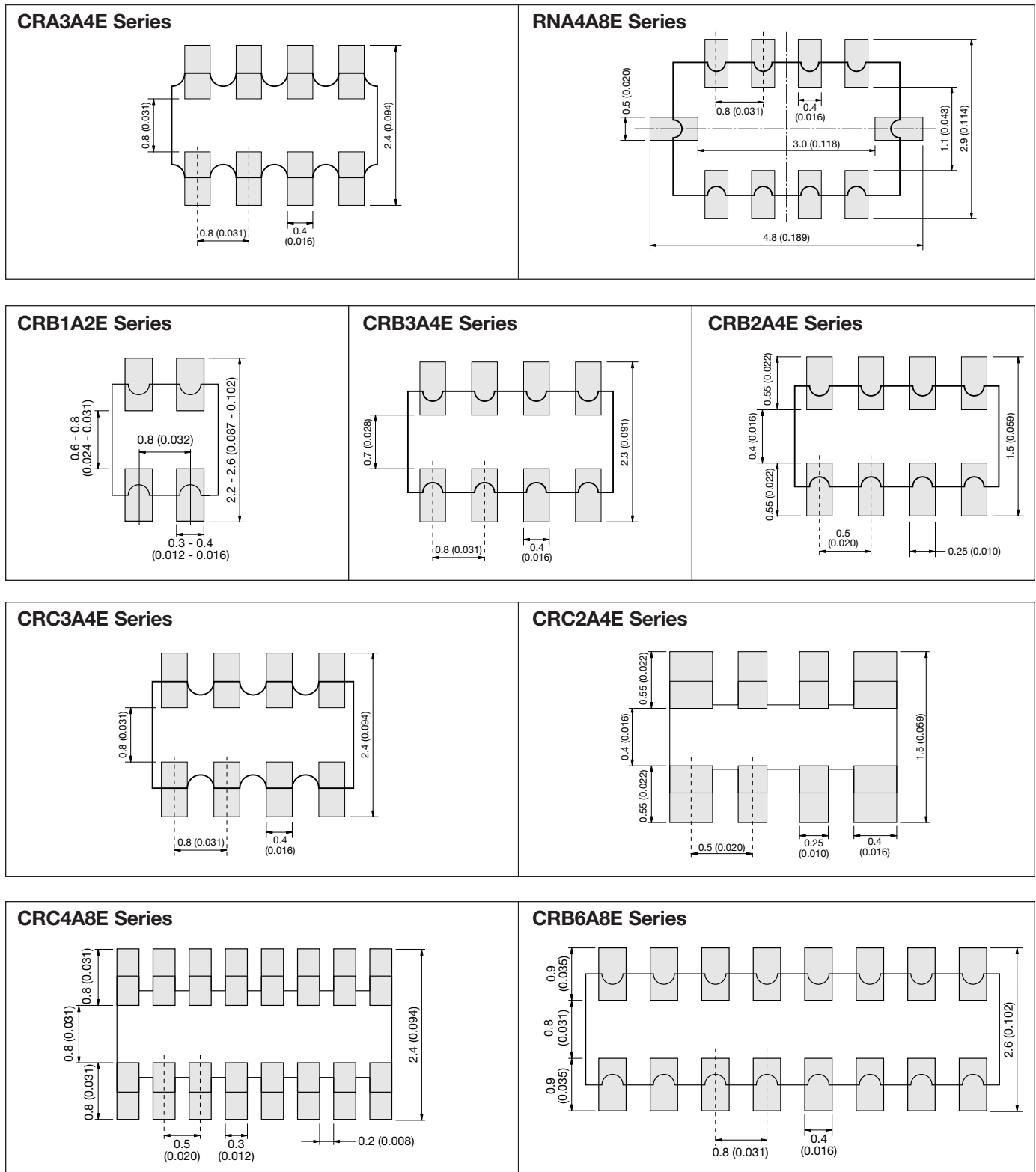


Recommended Land Patterns



RECOMMENDED LAND PATTERNS IS REFERRED THE FOLLOWING FOR EXAMPLE

millimeters (inches)



SAMPLE KIT PART NUMBERS

Part Number	Description
CRJ-E6-Kit	Combination 0603, 0805, 1206, 5% parts 21 values per case size 100 pcs. per value (approx.)
CR05-E12-Kit	0402, 5% parts 63 values 100 pcs. per value
CR10J-E12-Kit	0603, 5% parts 63 values 100 pcs. per value (approx.)
CR21J-E12-Kit	0805, 5% parts 63 values 100 pcs. per value (approx.)
CR32J-E12-Kit	1206, 5% parts 63 values 100 pcs. per value (approx.)
CR05F-E24-Kit	0402, 1% parts 63 values 100 pcs. per value
CR10F-E24-Kit	0603, 1% parts 63 values 100 pcs. per value
CR-ARRAY-E6-Kit	Arrays, Various styles, CRA, CRB, CRC, RNA, 5% 13 values per style (approx.) 20 pcs. per value